



Introduction

M series is a simple wafer test probe platform based on college education and laboratory. Ergonomic design is simple to operate, compact structure design greatly reduces the space occupied by the equipment, under the premise of ensuring high precision testing, but also very cost-effective. The modular design of UPStart allows you to add multiple accessories for more performance, while supporting late extension loading and upgrading. If your test PAD is greater than 30um, the M series is one of your preferred devices in the lab.

Application Direction

Chip and LD/LED/PD test, PCB/ package device test, RF test, electrode /PAD test over 50 microns, IV/CV characteristic test of material/device, etc.

Product Feature

- Compact and sturdy frame structure design, stable performance
- Easy operation and quick start, reduce the training time of equipment use
- The modular structure of UPStart supports late expansion and upgrade of devices
- Chuck with 3 - stage vacuum adsorption control
- New upgraded chuck mobile platform
The needle seat platform with stronger adsorption
- TNT frame support structure design
The microscope bracket is designed with 360° rotation
- Adaptive shock absorbing base
- A variety of Micro Positioners matching

Model		SM-4	SM-6 mini	SM-6
Dimension		L 400mm*W 400mm*H 550mm	L 400mm*W 400mm*H 550mm	L 680mm*W 530mm*H 550mm
Weight (about)		30KG	35KG	40KG
Electricity Demand		220VC,50~60Hz		
Chuck	Size & Rotation angle	4", 360° Rotation	6", 360° Rotation	6", 360° Rotation
	X-Y Moving range	4" * 4"	4" * 4"	6" * 6"
	Moving resolution	10um		
	Sample fixed mode	Vacuum adsorption		
	Electrical design	Electrical Floating with Banana plug adapter, can be used as a backside electrode		
Platen	U Shape	6 Micropositioners available		8 Micropositioners available
	Microscope	360° Rotation, Z : 50.8 mm		
Microscope	Magnification	16~100X (200X as a option)		
	CCD Pixel	50W (Analog) / 200W (Digital) / 500W (Digital)		
	Micropositioner	X-Y-Z Moving range	12mm-12mm-12mm	
Mechanical resolution		10µm / 2µm / 0.7µm		
Current leakage accuracy		10pA / 100fA (with Shielding Box)		
Cable connectors		Banana head / Crocodile clip / Coaxial / Triaxial		
Optional Accessories	Hot chuck			Light intensity / wavelength testing
	Shielding box			RF Testing accessories
	Special Adapter			Active probe
	Vibration Free Table			Low current / Capacitance test
	Gold-plated chuck			Integration of intergral sphere
	Coaxial / Triaxial chuck			Fixture for Fiber optic coupler test
	Chuck quick Up/Down and fine adjustment option			Fixture of PCB / IC test
	Chuck rotation fine adjustment			Special Custom design